

L Number	Hits	Search Text	DB	Time stamp
1	1334898	JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:01
2	8072	((plurlality or multiple or several) near4 chips)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:01
3	1971938	((plurlality or multiple or several) near4 chips) near4 integr\$4	USPAT; EPO; JPO; DERWENT	2004/06/29 15:02
4	941	((plurlality or multiple or several) near4 chips) near4 integr\$4)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:02
5	3	((plurlality or multiple or several) near4 chips) near4 integr\$4) near10 sealed	USPAT; EPO; JPO; DERWENT	2004/06/29 15:03
6	5	((plurlality or multiple or several) near4 chips) near4 integr\$4) near10 seal\$3	USPAT; EPO; JPO; DERWENT	2004/06/29 15:03
7	19	((plurlality or multiple or several) near4 chips) near4 integr\$4) same seal\$3	USPAT; EPO; JPO; DERWENT	2004/06/29 15:03
8	1	((plurlality or multiple or several) near4 chips) near4 integr\$4) same (integrally adj3 seal\$3)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:04
9	1	((plurlality or multiple or several) near4 chips) near4 integr\$4) same (integrally near3 seal\$3)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:04
10	1	((plurlality or multiple or several) near4 chips) near4 integr\$4) and (integrally near3 seal\$3)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:04
11	13	((plurlality or multiple or several) near4 chips) and (integrally near3 seal\$3)	USPAT; EPO; JPO; DERWENT	2004/06/29 15:04
12	4	((plurlality or multiple or several) near4 chips) and (integrally near3 seal\$3) and (JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3))	USPAT; EPO; JPO; DERWENT	2004/06/29 15:05
13	2982	((plurlality or multiple or several) near4 chips) and (JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3))	USPAT; EPO; JPO; DERWENT	2004/06/29 15:05
14	736	((plurlality or multiple or several) near4 chips) same (JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3))	USPAT; EPO; JPO; DERWENT	2004/06/29 15:06
15	2717	714/724.ccls.	USPAT; EPO; JPO; DERWENT	2004/06/29 15:08
17	1225	324/73.1.ccls.	USPAT; EPO; JPO; DERWENT	2004/06/29 15:08
18	4	324/73.1.ccls. and ((plurlality or multiple or several) near4 chips) same (JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3))	USPAT; EPO; JPO; DERWENT	2004/06/29 15:08
19	18	714/724.ccls. and ((plurlality or multiple or several) near4 chips) same (JTAG or (IEEE adj2 "1149") or (boundary adj2 scan test\$3))	USPAT; EPO; JPO; DERWENT	2004/06/29 15:09
21	0	Miyachi-k\$.in. and 714/724.ccls.	USPAT; EPO; JPO; DERWENT	2004/06/29 15:10
22	0	Miyachi-k\$.in. and 324/73.1.ccls.	USPAT; EPO; JPO; DERWENT	2004/06/29 15:10
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